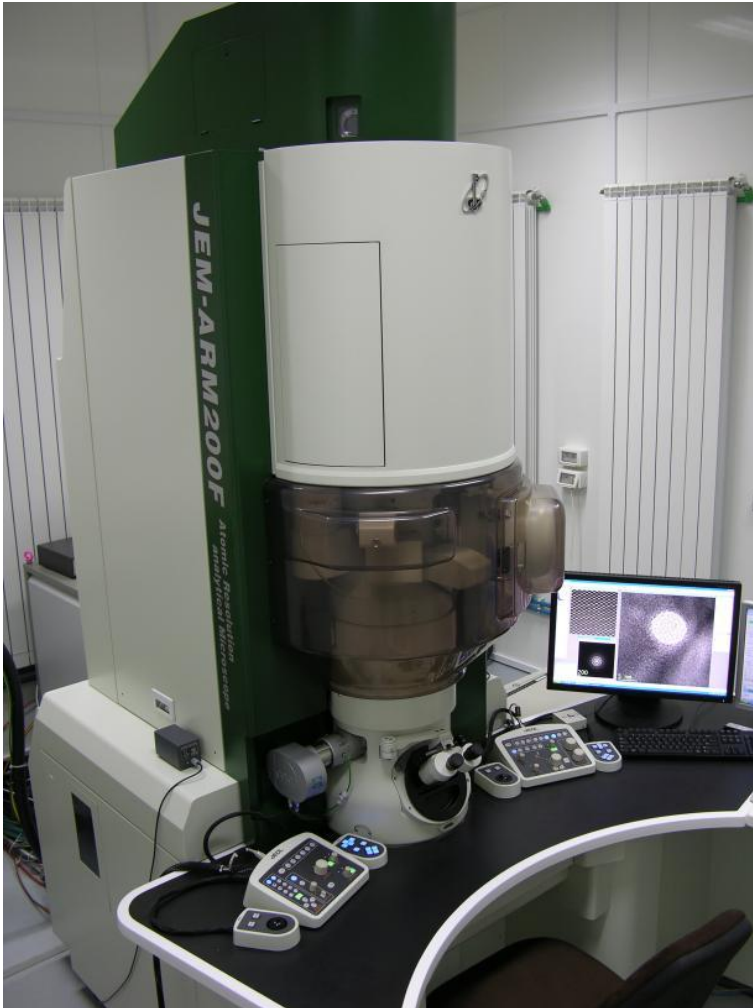


JEOL JEM ARM 200F

C_s-corrected Analytical High-Resolution Transmission Electron Microscope



Configuration

Field Emission Gun (FEG)

Cs-corrector for STEM mode

STEM Unit

EDS Unit: JEOL JED-2300T

EELS and Image Filter: Gatan Quantum SE

CCD Cameras:

- Gatan Orius 200D - wide angle port
- Gatan Ultrascan 1000XP - bottom mounted
- Gatan Ultrascan 1000FT - GIF camera

Working modes

CTEM, HRTEM, STEM BF, STEM ADF, STEM HAADF, SAED, nano-ED, CBED, EDS, EELS, EFTEM, EELS-SI

Technical specifications:

Accelerating voltages: 80, 120, 160, 200 kV

TEM magnification: 50 – 2 000 000 ×

TEM resolution: 0.19 nm

STEM magnification: 200 – 150 000 000 ×

STEM-HAADF resolution: 0.08 nm

EDS - energy resolution EDS: 131,4 eV (Mn-Kα)

- available in TEM mode;

- available in STEM mode: spot, line profile or 2D mapping;

EELS – energy resolution 0.7 eV